

ABSTRACT OF THE DISCLOSURE

A fixture is used to secure a substrate and to allow movement of a pin relative to the fixture. The substrate fixture includes a holding table adapted to receive the substrate and a probe pin assembly underneath the table. The substrate is mounted on a table which can move in one-dimension, while the probe pin is moveable relative to the table in another dimension perpendicular to movement of the table. Moving the substrate retaining table and the pin retainer allows for alignment of the probe pin with a backside terminal of a trace conductor of the substrate. The assembly also has vertical height translational mechanism for contacting the probe pin with the backside terminal. Furthermore, the frontside terminal of the trace conductor is accessible to an external probe. A testing device can be connected to the external probe and the probe pin to measure the electrical continuity of the trace conductor.

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